

Search Notes

Application/Control No.

10/705,347

Examiner

Kin-Chan Chen

Applicant(s)/Patent under
Reexamination

LABELLE ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	694	8/2/2005	KCC
	696		
	706		
	710		
	714		
	719		
	720		
438	722	8/2/05	K-cc

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST key words search, USPAT, US- PGPUB, EPO, JPO, Derwent, IBM- TDB, inventor search.	8/1/2005	KCC